

<b>Search Notes</b>  	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10630705	HEISHI ET AL.
	<b>Examiner</b>  Tecklu, Isaac T	<b>Art Unit</b>  2192

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
717	141, 146, 152	12/29/2006	IT

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST search, Inventor's search, Google search, NPL search (ACM, IEEE/Xplore)	12/29/2006	IT

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
717	141, 146, 152	12/29/2006	IT